



BSI Standards Publication

**Semiconductor devices — Reliability
test method by inductive load switching
for gallium nitride transistors**

National foreword

This British Standard is the UK implementation of EN 63284 Ed.1.0. It is identical to IEC 63284:2022.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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